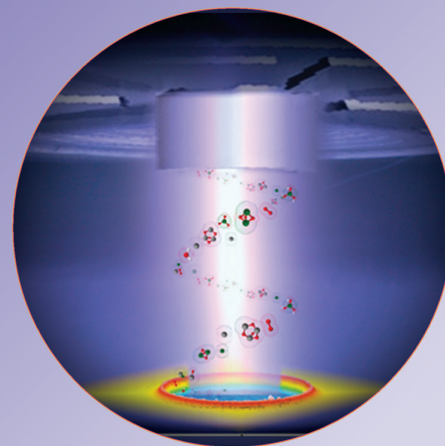
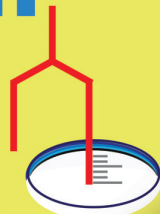


GD Day 2016

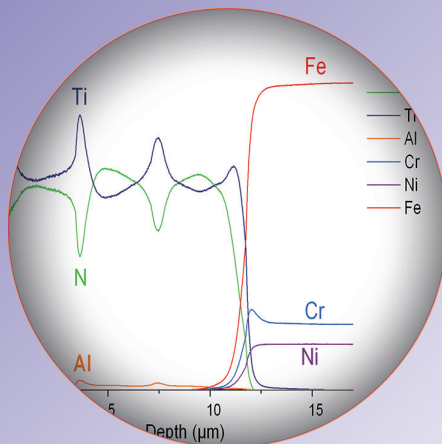
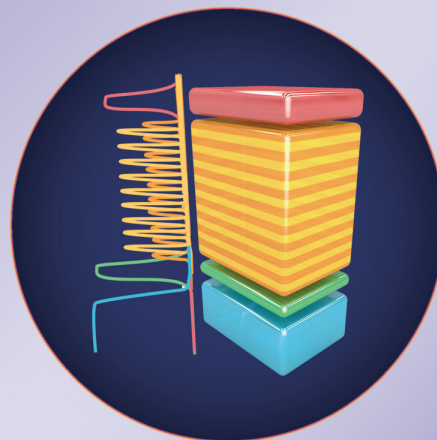
**15 afternoon
& 16
September 2016**



DiP



**8th
GD Day**



**For surface and
depth profile
analysis**

GD Day 2016

www.gd-day.com

Practical information

Registration

On-line registration to the GD Day is mandatory at www.gd-day.com.

Location

Synchrotron SOLEIL
L'Orme des Merisiers
rond point du Golf de Saint Aubin
91190 Saint Aubin

An identity card or a passport is mandatory to enter the site.

Poster guidelines

Poster boards are provided for poster presenters to display their posters.
Poster format is A0 vertical.
Posters will be on display during the whole symposium.

Synchrotron visit

A visit of the Synchrotron SOLEIL is organised on Thursday 15th afternoon. The visit is forbidden to people with pacemaker.

Gala Dinner

The Gala Dinner will be held at the Synchrotron Soleil on Thursday evening.
At 10:30 pm, bus will be ready for pick up and transfer to the RER stations.

Thursday 15 September 2016

13:30 Introduction of the GD Day

Patrick Chapon - HORIBA Scientific

13:40 GD Day - Session 1

Chair: Patrick Chapon, HORIBA Scientific, Palaiseau, France

13:45 **O1** Hydrogen Enhanced Oxidation: Atomic scale simulation and experimental evidences
T. Shoji, Tohoku University, Japan

14:10 **O2** Possibilities and limitations for analysis of chemical depth profiles in CdTe thin film solar cells
O. Zywitski, FEP, Germany

14:35 Poster talks (3 min/poster) and workshops presentation - Part 1 -

P1 Breakthrough on GDOES analysis applied to rough metal surfaces
S. Cremer, Arcelor Mittal, France

P2 Influence of CIGS Surface Conditioning on GDOES Depth Profile Measurement Results
W. Hempel, ZSW, Germany

P3 Depth profiling protective coating titanium nitride based on glow discharge optical emission spectrometry
A. Bartrakov, MPEI, Russia (Presented by A. Kuznetsov)

P4 Depth profiling of Zr-Nb alloy after plasma immersion Titanium implantation and Hydrogen saturation
T. Priamuskho, University of Tomsk, Russia

P5 Use of complementary techniques for depth profiling of mobile screen protection covers
B. Bleisteiner, HORIBA, Germany (Presented by S. Gaiaschi)

P6 The use of GDOES in failure analysis and quality control
A. Raffaelli, University of Udine, Italy

P7 Ferroelectric materials with Tetragonal Tungsten Bronze (TTB) type structure : Synthesis and characterization
A. Laaraj, LIMAT University of Casablanca, Maroc

P8 Pulsed Radiofrequency Glow Discharge Time of Flight Mass Spectrometry for VOCs Analysis: Development of a New Source
N. Bordel, University of Oviedo, Spain

P9 Improvement of inorganic gas diffusion barriers by a low energy Ar plasma treatment
J.E. Bouree, PICM, France

W1 DIP Workshop
S. Gaiaschi, HORIBA, France

P10 Bulk analysis of trace elements in pure Au and Ag by Profiler HR
V. Galuschenko, Moscow Mint, Russia

P11 Smart solid sample analysis - some examples for direct analysis by Electrothermal Vaporisation as add-on for ICP
P. Perzl, Spectral Systems, Germany

- P12** Surface sample preparation for EPMA using GDOES
S. Khromov, NTNU, Norway
- P13** Optical characterization of thin films by spectroscopic ellipsometry
J.P. Gaston, HORIBA, France
- P14** A new film thickness measurement technique: Differential Interferometric Profiling - similarities and complementarities with ellipsometry
O. Acher, HORIBA, France
- P15** Characterization of CIGS solar cells through Glow Discharge Optical Emission Spectrometry and Differential Interferometry Profiling
S. Gaiaschi, HORIBA, France
- P16** Synergy of GD-OES & DIP with EDXRF techniques for layers thickness and elemental composition determination
J. Marciano, HORIBA, France

15 : 35 **GD Day - Session 2**

Chair: Yuriy Popov, HORIBA, Moscow, Russian Federation

- 15:40 **O3** Development and characterization of coatings on selected metals and alloys obtained by Plasma Electrolytic Oxidation
K. Rokosz, University of Koszalin, Poland
- 16:05 **O4** Plasma Profiling TOFMS analysis for microelectronic applications
Y. Mazel, CEA Leti, France

16:30 Poster talks (3 min/poster) and workshop presentation - Part 2 -

- P17** Antifungal activity against *Candida albicans* biofilm of composite layers based on silver doped hydroxyapatite-polydimethylsiloxanes
C.S. Ciobanu, NIMP, Romania
- P18** Structural and antimicrobial properties of silver doped hydroxyapatite thin films deposited on PDMS/Si
C.L. Popa, NIMP, Romania
- W2** HORIBA Device Monitor (HDM) applied to GDS
Y. Popov, HORIBA, Russia
- P19** Using power coupling efficiency for ALD thin film oxides quantification.
D. Frey, EMPA, Switzerland
- P20** Presentation of a calibration kit for GDOES
N. Higa, HORIBA, Japan
- P21** Preparation of Nanoparticle-Based Composite Coatings
O. Sublemontier, CEA, France
- P22** Evaluation of inhibitory effect of glycerol-iron oxide layers on MRSA
S.L. Iconaru, NIMP, Romania
- P23** XPS analysis of native oxide layers on GaSb (100) surface –application to depth profiling of AuGeNi/n-GaSb
R.V. Ghita, NIMP, Romania

8th International GD Day

- P24** Neon Plasma Jet at Atmospheric Pressure. Spatio-temporal distribution of ambient air species
L. Chauvet, University of Toulouse, France
- P25** Neon Plasma Jet at Atmospheric Pressure. Application to mass spectrometry detection of volatile samples
Ph Guillot, University of Albi, France
- P26** Structural and biological evaluation of iron oxide-dextran nanostructures thin films
A.M. Prodan, Hopital Floreasca Bucharest, Romania
- P27** Improving layer thickness determination by the combination of depth profile modeling and DiP
M. Laquittaine, ENSSAT, Lannion, France
- P28** Optimizing GDOES sputtering of metal/polymer multilayer systems by plasma gas switching during the test
A. François-Heude, Vallourec Research Center France. France
- W3** HJY Service for GD
R. Toutain, HORIBA, France
- P29** New strategies to improve the analytical performance of pulsed glow discharge time of flight mass spectrometry
L. Lobo, University of Oviedo, Spain
- P30** Glow Discharge Optical Emission Spectrometry and Differential Interferometry Profiling for thickness determination of SiO_xN_y layers
S. Gaiaschi, HORIBA, France
- P31** Characterization and corrosion behaviour of pure titanium in sulfuric medium
S. Dubent, CNAM Paris, France
- P32** GD-OES crater engineering: the challenge of wet chemical and/or Ar cluster sputtering curing for nanometric XPS analyzes
A. Loubat, ILV, France
- P33** GD group on LinkedIn.
V. Naik, ASE India
- P34** Scaling Laws Between Mono And Multi-point Configuration In Positive DC Corona Discharge In Air
D. Raouti, University of Saida. Algeria
- P35** Measurement of homogeneity of reference materials of special alloys by GD - atomic emission spectrometry
I. Ermakova, Vniiofi Russia.
- P36** Corrosion product films on Mg alloys
P. Volovitch, ENSCP, Paris, France
- P37** Local Electrochemical Techniques Used For Spatially-Resolved Surface Analysis
S. Verret, Bio-Logic SAS, Seyssinet-Pariset, France
- P38 - P40** To be defined

17:30 Coffee break, poster session and Synchrotron visit

19:20 Cocktail

19:45 Gala Dinner at the Synchrotron Restaurant

Friday 16 September 2016

9:00 GD Day Session 3

Chair: *Sofia Gaiashi, HORIBA Scientific, Palaiseau, France*

- 9:05 **05** Novel Use of Glow Discharge Optical Emission Spectroscopy (GDOES) to Study Corrosion of AA2024 T3 in the Presence and Absence of Inhibitors
R. Bingham, University of Manchester, UK
- 9:30 **06** Challenge on depth profiling characterizations by combining GD-DIP and XPS: the absolute GGI determination!
A. Loubat, ILV, France
- 9:55 **07** Electrochemical analyses of intermetallic layers in Zn/Mg coating exposed by controlled GD sputtering of the coating
A. Lanzutti, University of Udine, Italy
- 10:20 **08** The Study of Ionic Migration in Perovskite film by GD-OES
H. Lee, PICM, France

10:45 Coffee break and poster session

11:15 GD Day Session 4

Chair: *O. Acher, HORIBA Scientific, Palaiseau, France*

- 11h20 **09** Applications of GD-TOFMS for Direct Analysis of Innovative Materials
J. Pisonero, University of Oviedo, Spain
- 11h45 **010** Characterization of zinc-rich layers on aluminium
M. Stepanova, NTNU, Norway
- 12h10 **011** GDOES studies of minor alloying elements incorporation into oxide scales during high temperature oxidation of Ni-based superalloys
W. Nowak, Rzeszow, Poland

12:35 Lunch and poster session

8th International GD Day

14:30 GD Day Session 5

Chair: S. Richard, HORIBA Scientific, Palaiseau, France

14h35 **O12** Hydrogen PEM electrolysis: used of GD-OES for fast characterization of innovative coating
N. Queromes, Areva, France

15h00 **O13** Magnetically Boosted Glow Discharge Optical Emission Spectroscopy for Analytical Applications: Pros and Cons
N. Bordel, University of Oviedo, Spain

15h25 **O14** GD-OES/Raman coupling for minor phases detection in photovoltaic thin film materials
G. Altamura, IPVF, France

15:50 **O15** Characterization of thin films on glass by GD-OES
H. Montigaud, St Gobain, France

16h15 Round Up & Conclusion of the 8th GD Day.

End of the 8th GD Day